



Docket No.: 015675.P372

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Dominique Barthel et al.,

Serial No: 09/936,487

Filing Date: January 25, 2002

For: **METHOD FOR TESTING
INTEGRATED CIRCUITS WITH
MEMORY ELEMENT**

Examiner: Gandhi, Dipakkumar B

Art Unit: 2133

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Technology Center 2100

Mail Stop - AMENDMENTS
Commissioner for Patents
PO Box 1450
Alexandria, Virginia 22313-1450

**REQUEST FOR EXTENSION OF TIME
AND
AMENDMENT AND RESPONSE TO OFFICE ACTION**

Dear Commissioner:

In response to the outstanding Office Action mailed June 17, 2004, please amend the above-identified application as follows:

09/28/2004 YPOLITE1 00000053 09936487

01 FC:1251 110.00 OP

09/28/2004 YPOLITE1 00000053 09936487

02 FC:1202 162.00 OP